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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

SUGIHARA ET AL.

Atty. Ref.: 1035-616

Serial No. 10/560,907

Group: 2131

Filed: December 16, 2005

Examiner: Unknown

For: SEMICONDUCTOR DEVICE, MANUFACTURING
METHOD THEREOF, AND ELECTRONIC DEVICE

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Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

Sir:

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

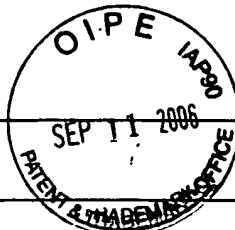
Further to applicants' Information Disclosure Statement of July 26, 2006, applicants herewith submit a corrected Form PTO-1449 (i.e., the date of the second article (Carcia et al reference) has been corrected).

Respectfully submitted,
NIXON & VANDERHYE P.C.

September 11, 2006

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**INFORMATION DISCLOSURE
CITATION**

ATTY. DOCKET NO.

1035-616

APPLICANT

SERIAL NO.

10/560,907

(Use several sheets if necessary)

SUGIHARA ET AL.

FILING DATE

GROUP

December 16, 2005

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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	6,727,522	4-2004	Kawasaki et al.			
	6,878,962	4-2005	Kawasaki et al.			

FOREIGN PATENT DOCUMENTS

DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
					YES	NO
2000-150900 A	5-2000	JP			partial	
2000-277534 A	10-2000	JP			partial	
2002-76356 A	3-2002	JP			partial	
63-101740 A	5-1988	JP			partial	

OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

	Hoffman et al, "ZnO-based transparent thin-film transistors", Applied Physics Letters, vol. 82, no. 5, 3 February 2003, pp.733-735
	Carcia et al, "Transparent ZnO thin-film transistor fabricated by rf magnetron sputtering", Applied Physics Letters, vol. 82, no. 7, 17 February 2003, pp. 1117-1119
	Nishii et al, "High Mobility Thin Film Transistors with Transparent ZnO Channels", Jpn. J. Appl. Phys., vol. 42, 2003, Part 2, no. 4A 1 April 2003 ©2003 The Japan Society of Applied Physics, pp. L347-L349
*Examiner	Date Considered

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.

Form PTO-FB-A820 (Also PTO-1449)